PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10067819	02/08/2002	~~324~~ 714	724	~~2153~~ 2858	Decady

**APPLICANTS: Matsubara Takayuki; Shimamura Akimitsu; KCRUS

**CONTINUING DATA VERIFIED: None

6/4/2004

** FOREIGN APPLICATIONS VERIFIED: YES 6/4/2004

JAPAN 2001-136938 05/08/2001

PG-PUB | DO NOT PUBLISH ☐ | RESCIND ☐

Foreign priority claimed	☒ yes ☐ no	ATTORNEY DOCKET NO
35 USC 119 conditions met	☒ yes ☐ no	60188-150
Verified and Acknowledged Examiners's intials		

TITLE : Integrated circuit and testing method for integrated circuit

U.S.DEPT. OF COMM./PAT.& TM-PTO-436L(Rev. 12-94)

NOTICE OF ALLOWANCE MAILED	Assistant Examiner	CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING	
Amount Due / Date Paid		Sheets Drwg. / Figs.Drwg. / Print Fig.	
☐ TERMINAL DISCLAIMER	Primary Examiner	Application Examiner	
	PREPARED FOR ISSUE		

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